

MX-SZ2M

Compound MATERIAL Microscope

AN IDEAL SOLUTION FOR DETECTING LARGE PARTICLES

It is ideal for the measurement of particle length and breadth as well as for differentiating between reflective and non-reflective particles.



SYSTEM FEATURES

- ❖ High optical performance
- ❖ ISO conformed detection of particles down to 20 μm
- ❖ Differentiation between reflective (metallic) and non-reflective (plastic) particles
- ❖ Automatic storage of magnification and camera settings for each configuration
- ❖ Compact design, No parallax error as on stereo microscopes, due to single beam particle size.

Test & Measurement

Length Graphite

ID	Max. Feret Diameter	Surface Area	Perimeter	Roundness	Round Categ	Linez Cate
1	0	1	1	Infinity		8
2	1	2	2	2.55		5
3	1	2	2	2.55		5
4	3.61	6	9	0.59	temp...	3
5	12.69	23	29	0.37	Vermi...	1
6	9.27	16	22	0.38	Vermi...	2
7	1	2	2	2.55		5
8	1.41	3	3	1.91		4
9	8.54	29	17	0.51	temp...	2
10	1.41	3	3	1.91		4
11	1	2	2	2.55		5
12	0	1	1	Infinity		8

Form Linear Graphite Area Ratio Classification

Form	ISO 945	Minimum Form	Maximum Form	Count	%
I	Lamellar (Flake)	0	0.15	31	4...
II	Crab Graphite	NaN	NaN	0	0
III	Compacted Vermic...	0.16	0.45	83	1...
IV	Temper Carbon (Irr...	0.46	0.6	31	4...
V	Slightly irregular Sp...	0.61	0.8	48	6...
VI	Spheroidal (Nodular)	0.81	1	27	3...

Edit Analyse

